

| | | | | |
|-----------------------------------|---------------------------------------|--|---|-------------|
| Notice of References Cited | Application/Control No. 10/522,034 | | Applicant(s)/Patent Under Reexamination NAKAYAMA ET AL. | |
| | Examiner Susan W. Berman | | Art Unit 1711 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| * | A | US-5,214,116 | 05-1993 | Matsuoka et al. | 526/286 |
| * | B | US-6,551,710 | 04-2003 | Chen et al. | 428/412 |
| * | C | US-6,887,402 | 05-2005 | Klemm et al. | 264/1.24 |
| * | D | US-5,518,789 | 05-1996 | Burns et al. | 428/825 |
| * | E | US-5,908,876 | 06-1999 | Fujii et al. | 522/142 |
| * | F | US-5,741,831 | 04-1998 | Keita et al. | 523/106 |
| * | G | US-6,844,950 | 01-2005 | Ja Chisholm et al. | 359/456 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.